

# Quantitative Mesoscale Analysis of SOFC Electrodes Based on 3D Reconstructions using Xe-plasma Focused Ion Beam (PFIB) coupled with SEM

Research & Innovation Center



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## Introduction

**Electrode microstructures control performance of SOFCs and vary over the mesoscale**

• Key factors limiting the commercialization of SOFCs:

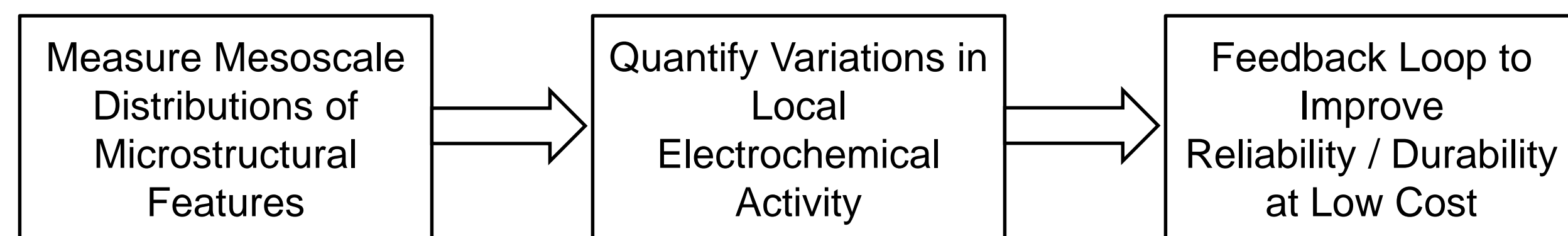
- I. High cost of manufacture
- II. Poor reliability
- III. Low durability

• A tradeoff exists between cost of manufacture and reliability / durability of electrodes:

Research-grade SOFC Samples	Commercial SOFC Samples
I. Higher-cost synthesis	I. Lower-cost synthesis
II. Ideal feedstock materials	II. Less perfect feedstock materials
III. Produced in low quantities	III. Mass Production
IV. Highly homogeneous microstructures	IV. Heterogeneous microstructures

• In commercial SOFCs, mesoscale ( $\approx$  hundreds of microns) microstructural variations are expected.

• How can we quantify the impact of mesoscale microstructural variations to processing / performance:



## Objectives:

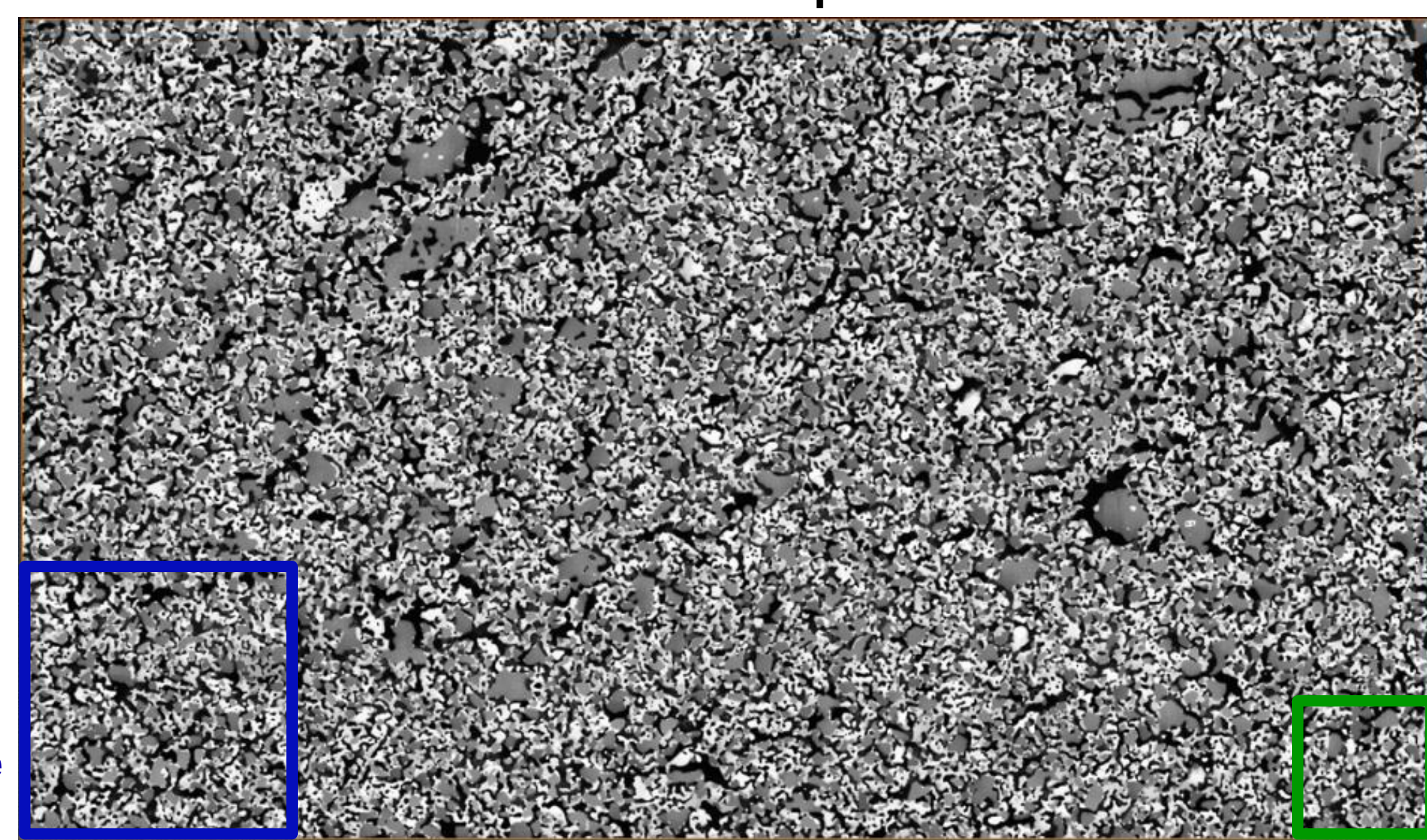
- To determine quantitatively the mesoscale distributions of microscale properties in SOFC electrodes using large volume / high resolution 3D reconstructions of commercial cells.
- To demonstrate correlations between outlier microstructural features and performance.

## Why Xe-PFIB-SEM ?

**PFIB can capture  $\approx 50-100x$  Ga-FIB area and  $\approx 10-50x$  nano-CT area in same amount of time**

- High material removal rate using Xe-plasma Focused Ion Beam (Xe-PFIB or PFIB)
- Nano-scale resolution using Scanning Electron Microscopy (SEM)
- Unprecedented large volume / high resolution 3d reconstructions in standard collection times

**Actual Xe-plasma-FIB Volume**  
126 x 73 x t  $\mu\text{m}^3$



t = thickness

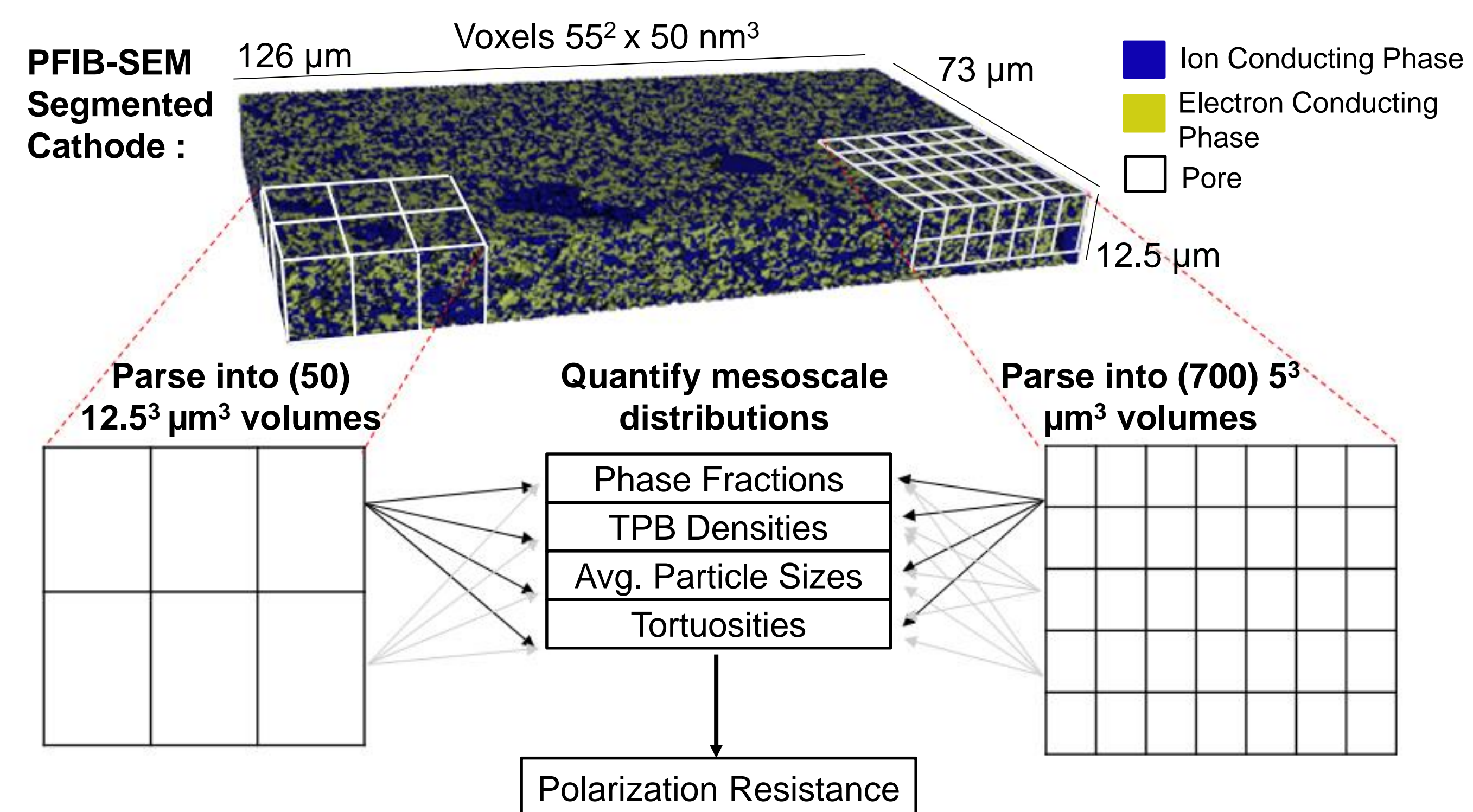
**Standard Ga-FIB Volume**  
12.5 x 12.5 x t  $\mu\text{m}^3$

## References:

- [1] J. Joos et al., Electrochim. Acta, Vol. 82, pp. 268–276, 2012.
- [2] W M Harris and W K S Chiu, J. Power Sources, Vol. 282, pp 552–561, 2015.
- [3] J. Scott Cronin et al., J. Electrochem. Soc., Vol.159, No.4, pp B385-B393, 2012.

## Approach to Quantify Mesoscale Distribution

**10s to 100s of microscale sub-volumes analyzed to generate mesoscale distributions of microstructural and performance parameters**



### Quantifying Microstructural Features:

- $\geq 5^3 \mu\text{m}^3$  is a standard microscale volume that describes local electrochemical activity [1,2]
- $5 \mu\text{m}^3$  and  $12.5 \mu\text{m}^3$  sub-volumes were analyzed using matlab codes for quantitative microstructural features

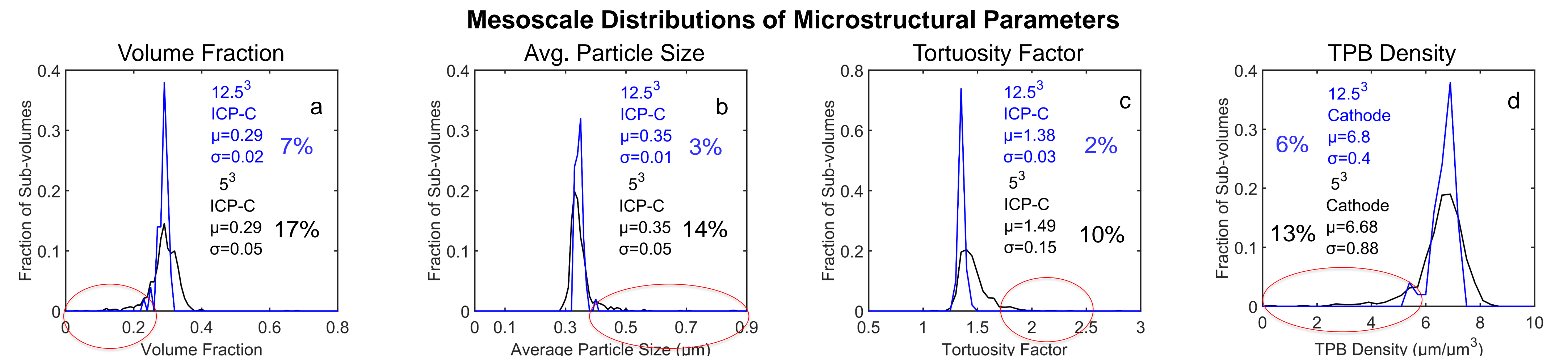
### Quantifying Polarization Resistance:

- Microstructural parameters taken as input to an effective medium theory model (TFV Model<sup>[3]</sup>)  $\rightarrow$  outputs area specific polarization resistance (ASR)
- Distributions in local ASR are obtained and mapped

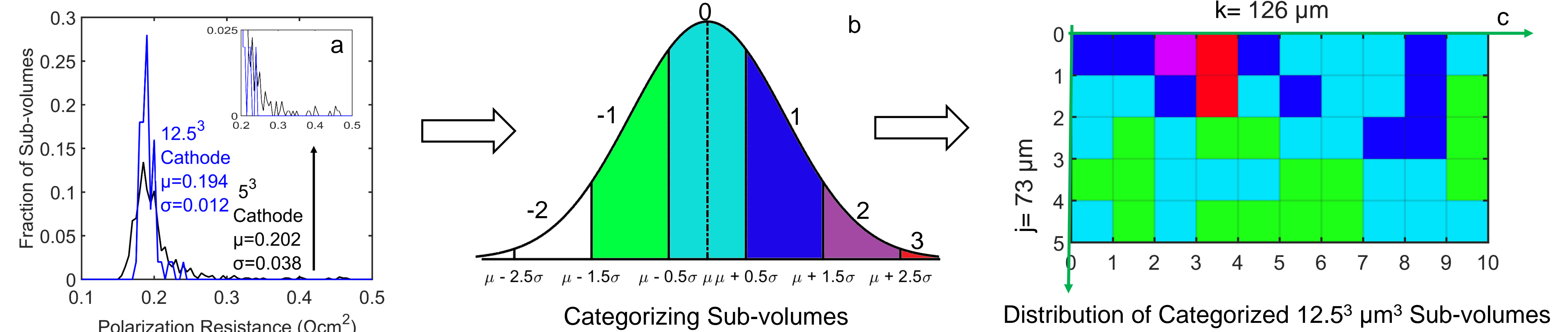
Assumption for TFV Model	Microstructural Inputs for TFV Model
<ul style="list-style-type: none"> <li>➢ Cathode TPB-line Resistivity (<math>800^\circ\text{C}</math>) <math>\rho_{\text{ct}} = 1.9 \times 10^5 \Omega\text{cm}^{-1}</math></li> <li>➢ ICP Conductivity <math>\sigma_{\text{O}_2} = 0.055 \text{ Scm}^{-1}</math></li> </ul>	<ul style="list-style-type: none"> <li>➢ Cathode Thickness</li> <li>➢ Volume Fraction of Phases</li> <li>➢ Average ICP Particle Size</li> <li>➢ ICP Tortuosity Factor</li> <li>➢ TPB Density</li> </ul>

## Results Visualization

**Microstructural distributions are skewed, with one tail being more populated than the other**



### Mesoscale Distributions of Polarization Resistance:



**Local ASR values exist that are well outside the average values**

**Outliers that are expected to impact long term performance can be quantified using PFIB-SEM**

## Conclusions

- A commercial SOFC electrode was found to exhibit significant variations in its mesoscale distributions of local microstructural features.
- These variations in mesoscale microstructural features are found to result in significant variations in electrochemical activity throughout the electrode.
- The distribution of local polarization resistance around the mean indicates that some local areas are well outside the average.
- This work offers a path to analyzing the impact of local heterogeneities on long-term cell performance and to optimizing microstructural distributions.